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#	Articles published in journals	 in kB
A1	K.H. Gaukler and R. Schwarzer Verbessertes Verfahren zur Bestimmung des mittleren inneren Potentials aus Reflexions-Kikuchi-Diagrammen. Optik 33 (1971) 215-229	424
A2	K.H. Gaukler and R. Schwarzer Elektronen-Emissions-Mikroskopie (Review article). Messtechnik 81 (1973) 307-316	1.190
A3	J. Hofmeister and R. Schwarzer Zum Einfluß der kristallographischen Orientierung auf den vektoriellen Photoeffekt. Physics Letters 53A (1975) 283-284	501
A4	G.H. Hartmann, H.P. Niemitz and R.A. Schwarzer Bestimmung des mittleren inneren Potentials von Diamant und von Vanadium-Pentoxid aus Reflexions-Kikuchi-Diagrammen. Optik 44 (1975) 37-43	488
A5	R. Schwarzer Der Einfluß von Loch- und Ringblenden auf die Energieverteilung der Elektronen im Emissions-Elektronenmikroskop. Optik 44 (1975) 61-78	1.078
A6	R. Schwarzer Die Verbesserung des Bildkontrastes im Emissions-Elektronenmikroskop durch eine ringförmige Aperturblende. Optik 44 (1975) 121-131	533
A7	M.B. Trullenque, Z.P. Argüello and R.A. Schwarzer Investigations of ionic crystals with the photoemission electron microscope. Revista Microscopia Electrónica 3 (1976) 156-157	252
A7a	R.A. Schwarzer, J.I. Cisneros, M. Tomyiama, Shih-Lin Chang and Z.P. Argüello Study of orientation contrast and information depth in LiF with the photoemission electron microscope (PEEM). Revista de Microscopia Electrónica 5 (1978)	288
A8	W. May, E.A. Farah and R. Schwarzer EMA and PEEM studies of WC-Ti interface reactions. Revista Microscopia Electrónica 3 (1976) 190-191	390
A9	R. Schwarzer and K.H. Gaukler Erzeugung einer Ionen-Mikrosonde mittels Feldionisation und Emissionslinse. Vakuum-Technik 27 (1978) 2-5	81
A10	R. Schwarzer Die Bestimmung von Strukturpotentials aus Kossel-Möllenstedt-Diagrammen an epitaktisch aufgedampften, freitragenden Kupfereinkristallschichten. Optik 54 (1979) 193-199	190
A11	R.A. Schwarzer Emission electron microscopy - A review. Part 1: Basic concepts and applications in physics. Microscopica Acta 84 (1981) 51-86	1.961
A12	R.A. Schwarzer Bestimmung von Polfiguren und Texturanalyse mit dem Transmissions-Elektronenmikroskop. Z. Metallkunde 73 (1982) 495-498	507
A13	R.A. Schwarzer On-line measurement of foil thickness from Kossel-Möllenstedt diffraction patterns. Optik 77 (1987) 55-56	179
A14	R.A. Schwarzer and H. Weiland Texture analysis by the measurement of individual grain orientations - Electron microscopical methods	1.459

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A15	R.A. Schwarzer Measurement of local textures with transmission and scanning electron microscopes. Textures and Microstructures 13 (1990) 15-30	1.502
A16	R. Schwarzer Die Kristalltextur in der Mikroelektronik. Teil 1. Elektronenmikroskopische Meßverfahren. Verbindungstechnik in der Elektronik 3 (1991) Heft 1, 16-20 Teil 2. Hügelbildung in dünnen Metallisierungsschichten. Verbindungstechnik in der Elektronik 3 (1991) Heft 2, 56-59	1.419
A17	R.A. Schwarzer A review of the analysis of local texture by electron diffraction. Textures and Microstructures 14-18 (1991) 85-90	799
A18	R.A. Schwarzer Scanning X-ray apparatus for texture mapping by energy dispersive diffraction. Textures and Microstructures 14-18 (1991) 241-244	478
A19	R.A. Schwarzer Texture analysis by electron diffraction. Steel Research 62 (1991) 542-547	1.614
A20	D. Gerth, D. Katzer and R. Schwarzer Correlation between grain growth and hillock growth in thin thermally annealed Al-1%Si films on silicon substrates. Materials Science Forum 94-96 (1992) 557-562 / Proc. Intern. Conf. on Grain Growth in Polycrystalline Materials, Rome 1991	273
A21	D. Gerth and R.A. Schwarzer The development of grain-specific texture and grain boundary character during grain growth of Al-1%Si films on SiO ₂ /Si substrates. Materials Science Forum 113-115 (1993) 619-624 / Proc. Intern. Conf. on Recrystallization and Related Phenomena (Recrystallization '92), San Sebastian 1992	126
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A23	S. Zaefferer and R.A. Schwarzer Microstructure and local texture of partially recrystallized titanium sheet. Materials Science Forum 113-115 (1993) 721-724 / Proc. Intern. Conf. on Recrystallization and Related Phenomena (Recrystallization '92), San Sebastian 1992	114
A24	R.A. Schwarzer Crystal texture analysis of ceramics by electron microscopy. Ceramika 42 (1993) 59-65 / Polski Biuletyn Ceramiczny 4 (1993)	100
A25	R.A. Schwarzer The determination of local texture by electron diffraction - A tutorial review. Textures and Microstructures 20 (1993) 7-27	3.495
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A28	R.A. Schwarzer Texture distributions imaged by energy dispersive x-ray diffraction. Steel Research 64 (1993) 570-574	1.157
A29	R.A. Schwarzer A CCD camera system for the acquisition of backscatter Kikuchi patterns on an SEM. Materials Science Forum 157-162 (1994) 187-188 / Proc. ICOTOM 10, Clausthal 1993	100
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A31	R.A. Schwarzer and S. Zaefferer On-line interpretation of SAD channeling patterns. Materials Science Forum 157-162 (1994) 195-200 / Proc. ICOTOM 10, Clausthal, 1993	176
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A33	S. Zaefferer and R.A. Schwarzer On-line determination of complete deformation systems for cubic and hexagonal crystals in the TEM. Materials Science Forum 157-162 (1994) 241-246 / Proc. ICOTOM 10, Clausthal 1993	383
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A36	M. Barthel, D. Gerth, R.A. Schwarzer, P. Klimanek and U. Messerschmidt Individual grain orientation relations after high-speed hot rolling of steel rods. Materials Science Forum 157-162 (1994) 1131-1136 / Proc. ICOTOM 10, Clausthal 1993	479
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A41	K. Helming, R.A. Schwarzer, B. Rauschenbach, S. Geier, B. Leiss, H.-R. Wenk, K. Ullemeyer and J. Heinitz Texture estimates by means of components. Z. Metallkunde 85 (1994) 545-553	1.627
A42	M. Wehrhahn and R.A. Schwarzer Crystal texture mapping by energy dispersive x-ray diffraction. Z. Metallkunde 85 (1994) 581-584	321
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A48	K. Helming, B. Rauschenbach and R.A. Schwarzer Analysis of crystallographic texture in small sample areas. Textures and Microstructures 26-27 (1996) 111-124	899
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A57	A. Huot, R.A. Schwarzer and J.H. Driver Texture of shear bands in Al-Mg3% (AA5182) measured by BKD. Materials Science Forum 273-275 (1998) 319-326	493
A58	A. Ziegenbein, H. Neuhäuser, J. Thesing, R. Ritter, H. Wittich, E. Steck, F. Springer and R.A. Schwarzer Investigations on local plasticity of CuAl polycrystals by in-situ observations and FEM simulations. Materials Science Forum 273-275 (1998) 363-368	264
A59	M. Lepper, A. von Glasow, D. Piscevic and R.A. Schwarzer Crystal texture and electromigration damage in Al-based interconnect lines studied by ACOM with the SEM. Materials Science Forum 273-275 (1998) 573-577	193
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A62	R.A. Schwarzer Crystallography and microstructure of thin films studied by X-ray and electron diffraction. Materials Science Forum 287-288 (1998) 23-60 Proc. 6th Intern. Symposium on Trends and New Applications of Thin Films, Regensburg 18-20 March 1998	911
A63	R.A. Schwarzer Automated crystal orientation mapping (ACOM) - a new perspective on the characterization of microstructure. Bulletin Czech and Slovak Crystallographic Association 5 (1998) 35-36 (Special Issue A - ECM-18)	89
A64	H.J. Bunge and R.A. Schwarzer Orientierungsstereologie - ein neuer Zweig der Texturforschung. TU Contact 2 (1998) 67-73	2.093
A65	S. Kittelberger, U. Bolz, R.P. Huebener, B. Holzapfel, L. Mex and R.A. Schwarzer Transient local resistivity maximum during temperature dependent oxygen diffusion in YBa ₂ Cu ₃ O _{7-δ} thin films. Physica C 312 (1999) 7-20	2.887
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A75	R.A. Schwarzer EBSD studies of interconnect lines. Revue de Métallurgie - SF2M - JA2001 (2001) 65	181
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A83	R.A. Schwarzer Texture in hot extruded, hot rolled and laser welded magnesium base alloys. Solid State Phenomena 105 (2005) 23-28	310
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A102	J. Sukkau and R.A. Schwarzer Reconstruction of Kikuchi patterns by intensity-enhanced Radon transformation. Pattern Recognition Letters 33 (2012) 739-743	390
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A105	R.A. Schwarzer and J. Hjelen Backscattered electron imaging with an EBSD detector. Microscopy Today 23 January Issue (2015) 12-17	2.062
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C13	R.A. Schwarzer Determination of fibre textures in thin gold films by evaluating pole figures with the TEM. Proc. 10th Intern. Congress Electron Microscopy, Hamburg 1982, Vol. 2, 129-130	557
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